Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/648,316	NAMIKATA, TAKESHI	
Examiner	Art Unit	
Yixing Qin	2625	

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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(INCLUDING SEARCH	SIRAIEGI)
	DATE	EXMR
Performed searching for systems for detecting counterfeit copying	6/18/2007	YQ
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